

P08 LTE B13_QPSK10M_Right Cheek_Ch23230_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 13	LTE-FDD, -	782.000, 23230	10.21	0.898	43.6

Hardware Setup

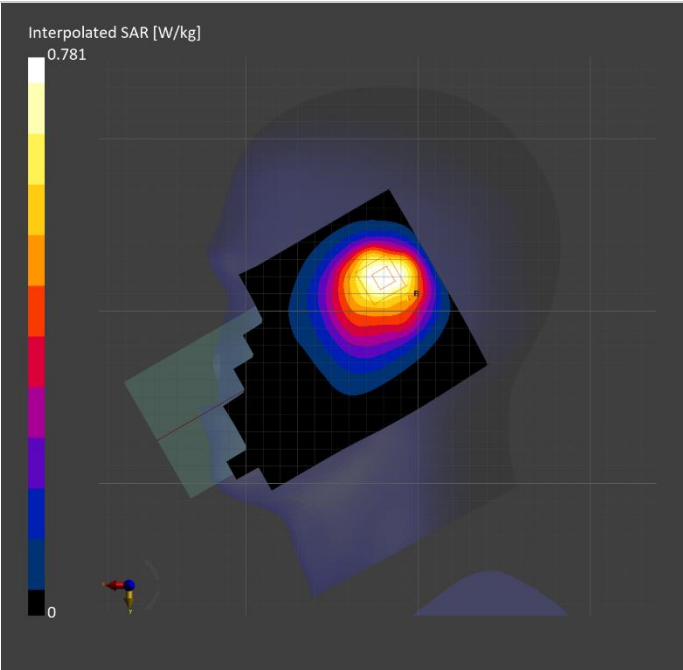
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL750-2025-04-25	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-25	2025-04-25
psSAR1g [W/kg]	0.684	0.731
psSAR10g [W/kg]	0.455	0.413
Power Drift [dB]	-0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.2
Dist 3dB Peak [mm]		8.5



P09 LTE B26_QPSK15M_Right Cheek_Ch26765_36RB_OS19

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 26	LTE-FDD, -	821.500, 26765	9.75	0.923	43.4

Hardware Setup

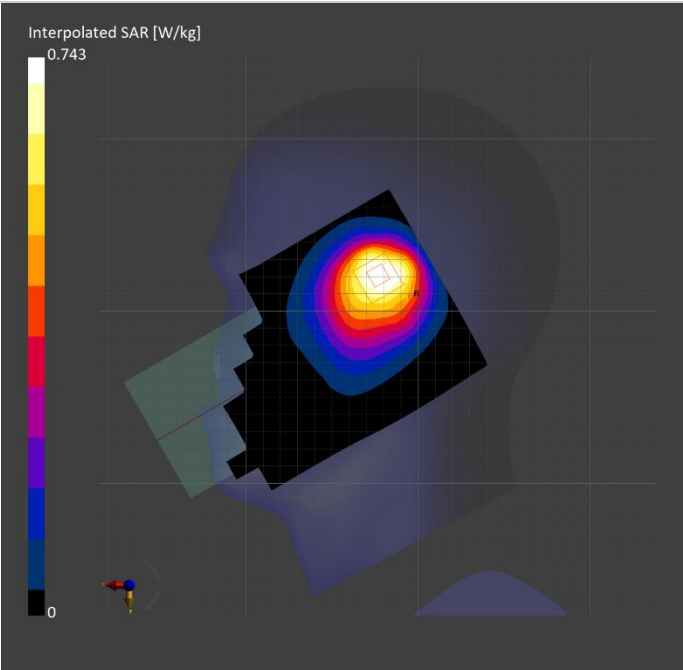
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-04-21	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-21	2025-04-21
psSAR1g [W/kg]	0.649	0.682
psSAR10g [W/kg]	0.435	0.398
Power Drift [dB]	0.00	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		73.9
Dist 3dB Peak [mm]		8.8



P10 LTE B41_QPSK20M_Right Tilted_Ch40620_50RB_OS25

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	TILT, 0.00	Band 41	LTE-TDD, -	2593.000, 40620	7.57	1.94	37.7

Hardware Setup

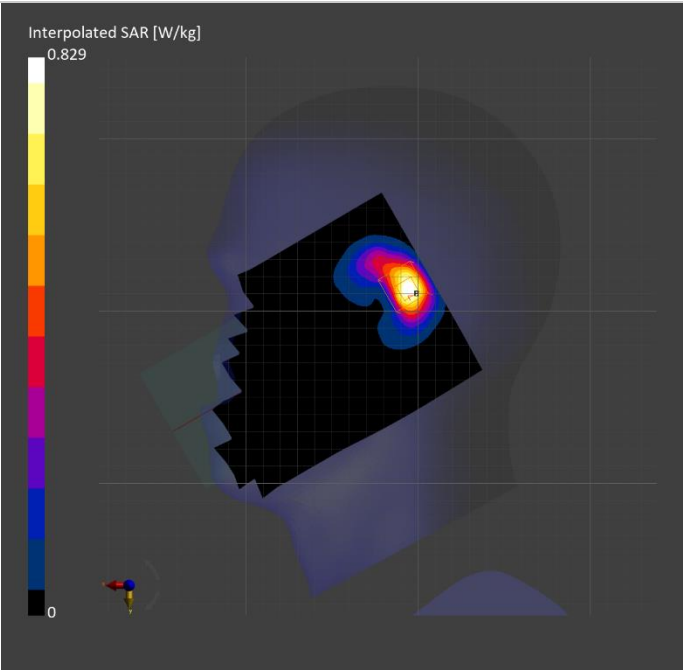
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-04-24	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-24	2025-04-24
psSAR1g [W/kg]	0.624	0.711
psSAR10g [W/kg]	0.289	0.298
Power Drift [dB]	0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.4
Dist 3dB Peak [mm]		6.4



P11 LTE B66_QPSK20M_Right Tilted_Ch132072_50RB_OS25

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	TILT, 0.00	Band 66	LTE-FDD, -	1720.000, 132072	8.6	1.32	41.5

Hardware Setup

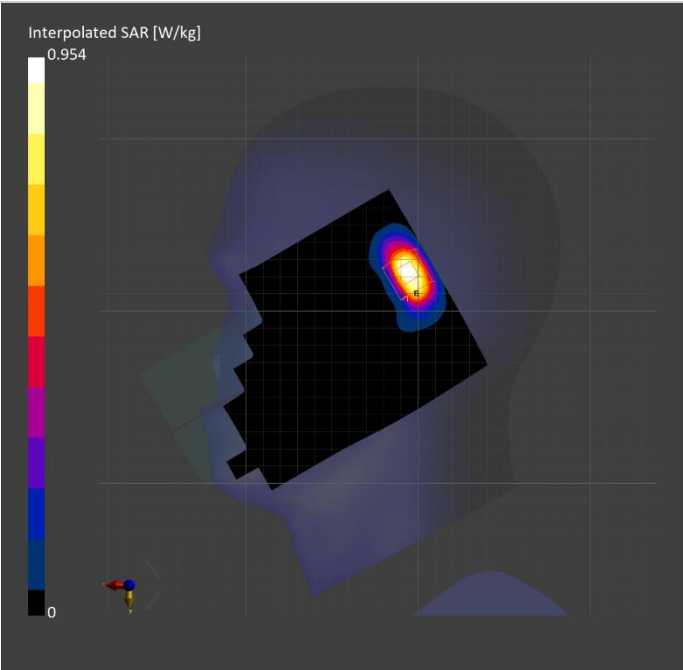
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-04-23	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-23	2025-04-23
psSAR1g [W/kg]	0.749	0.808
psSAR10g [W/kg]	0.370	0.381
Power Drift [dB]	-0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.2
Dist 3dB Peak [mm]		7.2



P12 WLAN2.4G_802.11b_Left Cheek_Ch1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	WLAN 2.4GHz	WLAN, -	2412.000, 1	7.7	1.79	41.0

Hardware Setup

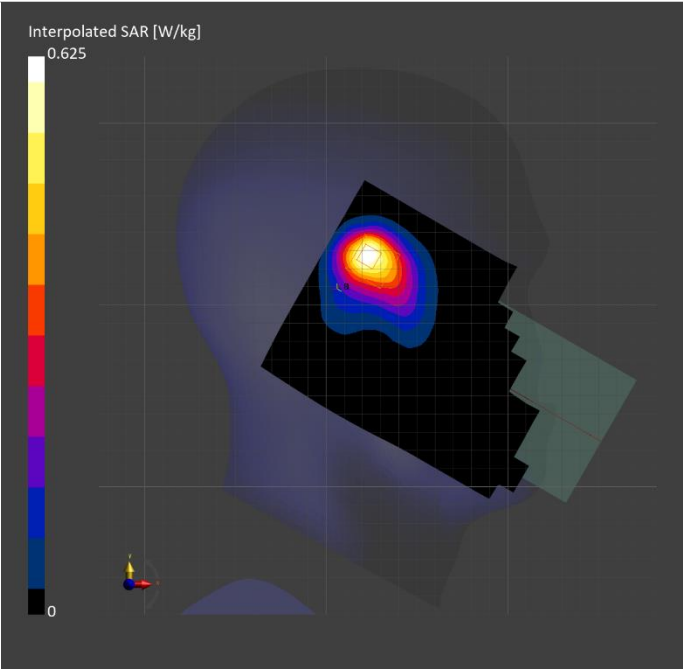
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-04-30	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-30	2025-04-30
psSAR1g [W/kg]	0.485	0.467
psSAR10g [W/kg]	0.248	0.240
Power Drift [dB]	-0.06	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.4
Dist 3dB Peak [mm]		8.1



P13 WLAN5G_802.11a_Left Titted_Ch60

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	TILT, 0.00	WLAN 5GHz	WLAN, -	5300.000, 60	4.99	4.65	36.2

Hardware Setup

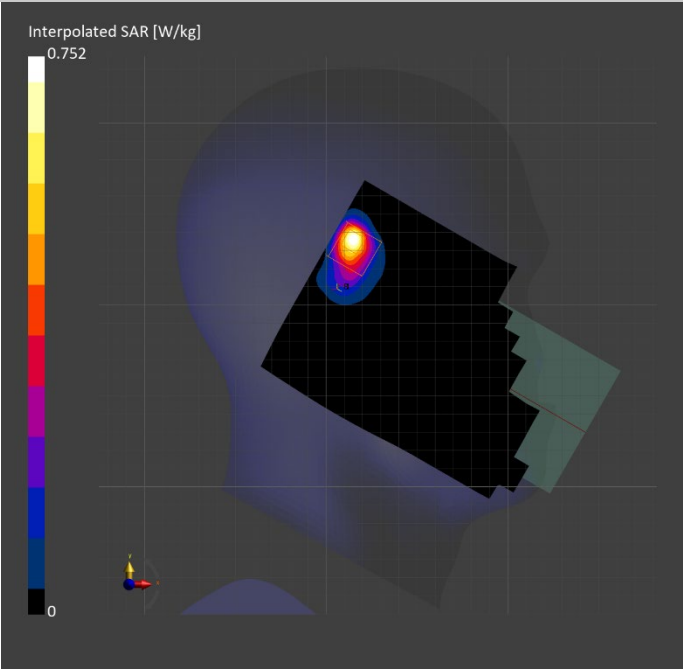
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-04-29	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-29	2025-04-29
psSAR1g [W/kg]	0.479	0.502
psSAR10g [W/kg]	0.157	0.139
Power Drift [dB]	-0.43	0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.5
Dist 3dB Peak [mm]		6.3



P14 WLAN5G_802.11a_Left Tilted_Ch100

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	TILT, 0.00	WLAN 5GHz	WLAN, -	5500.000, 100	4.65	4.88	35.8

Hardware Setup

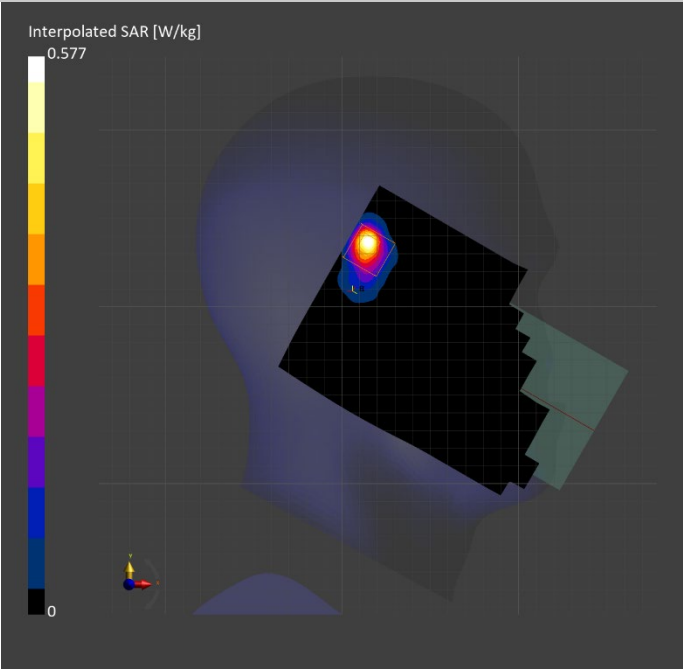
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-04-29	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-29	2025-04-29
psSAR1g [W/kg]	0.359	0.402
psSAR10g [W/kg]	0.110	0.104
Power Drift [dB]	0.02	0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		63.6
Dist 3dB Peak [mm]		5.8



P15 WLAN5G_802.11a_Left Tilted_Ch149

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	TILT, 0.00	WLAN 5GHz	WLAN, -	5745.000, 149	4.76	5.17	35.4

Hardware Setup

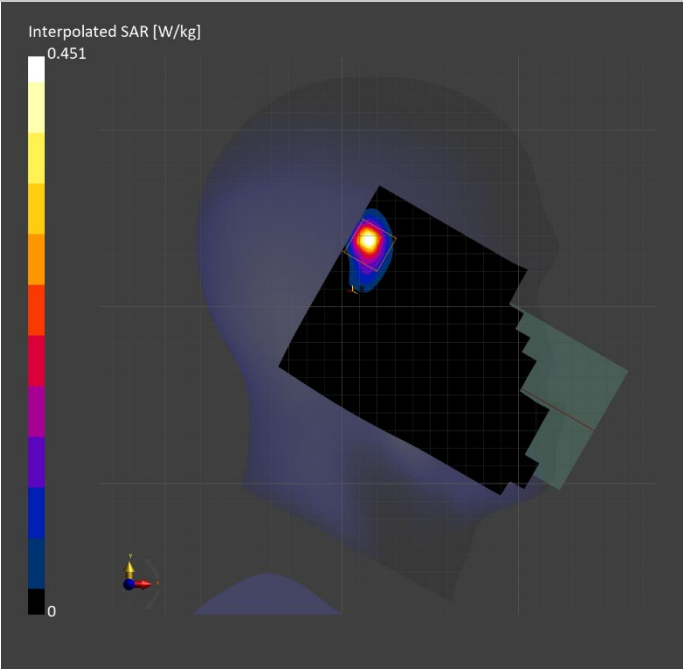
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-04-30	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-30	2025-04-30
psSAR1g [W/kg]	0.270	0.310
psSAR10g [W/kg]	0.076	0.073
Power Drift [dB]	0.22	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		56.9
Dist 3dB Peak [mm]		5.7



P16 BT_GFSK_Left Cheek_Ch39

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	ISM 2.4 GHz Band	Bluetooth, -	2441.000, 39	7.7	1.84	37.9

Hardware Setup

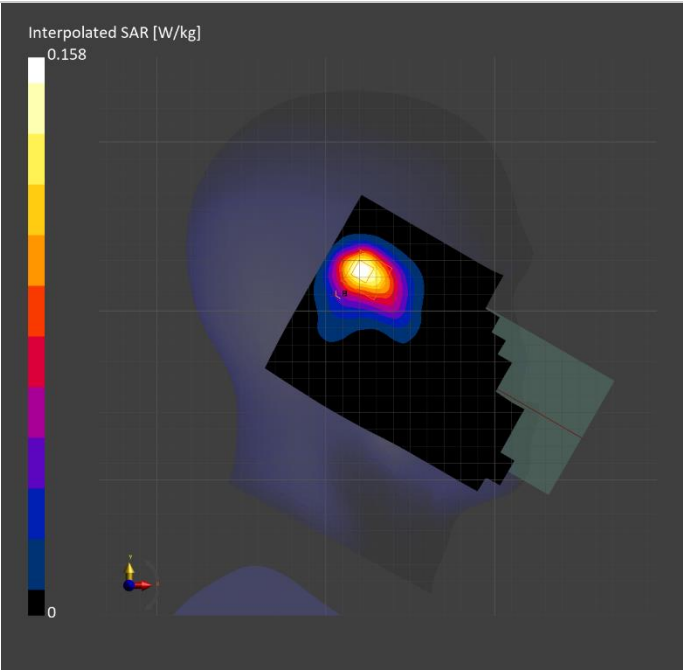
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-04-30	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-30	2025-04-30
psSAR1g [W/kg]	0.121	0.123
psSAR10g [W/kg]	0.060	0.062
Power Drift [dB]	0.07	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.2
Dist 3dB Peak [mm]		11.2



P17 GSM850_GPRS 1Tx Slot_Rear Face_1.5cm_Ch251

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	GSM 850	GSM, -	848.800, 251	9.75	0.926	43.4

Hardware Setup

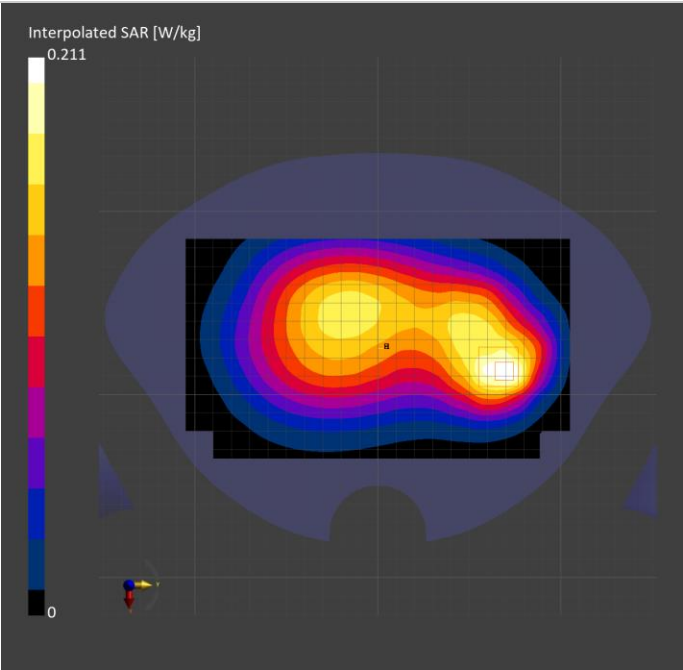
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-04-21	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-21	2025-04-21
psSAR1g [W/kg]	0.181	0.178
psSAR10g [W/kg]	0.120	0.109
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.0
Dist 3dB Peak [mm]		14.0



P18 GSM1900_GPRS 1Tx Slot_Rear Face_1.5cm_Ch661

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	PCS 1900	GSM, -	1880.000, 661	8.25	1.38	40.8

Hardware Setup

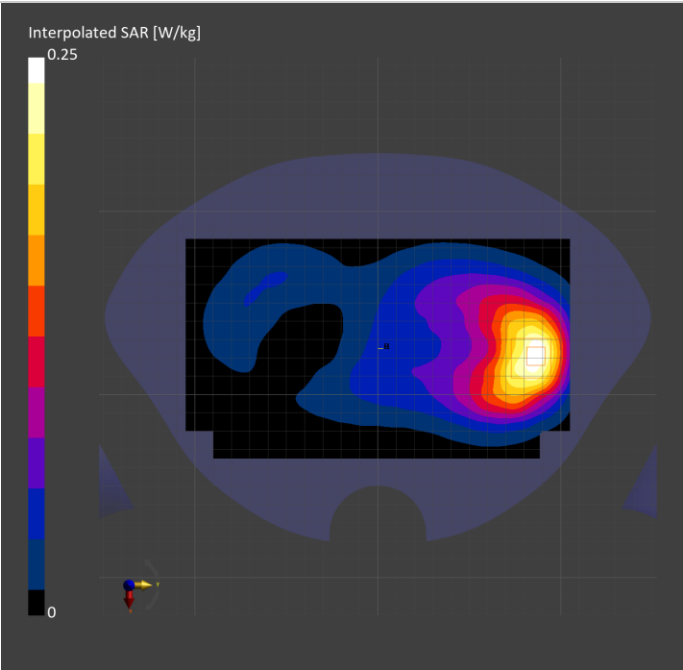
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-04-22	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-22	2025-04-22
psSAR1g [W/kg]	0.204	0.219
psSAR10g [W/kg]	0.122	0.129
Power Drift [dB]	-0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.0
Dist 3dB Peak [mm]		14.1



P19 WCDMA II_RMC12.2K_Rear Face_1.5cm_Ch9262

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 2	WCDMA, -	1852.400, 9262	8.25	1.37	40.9

Hardware Setup

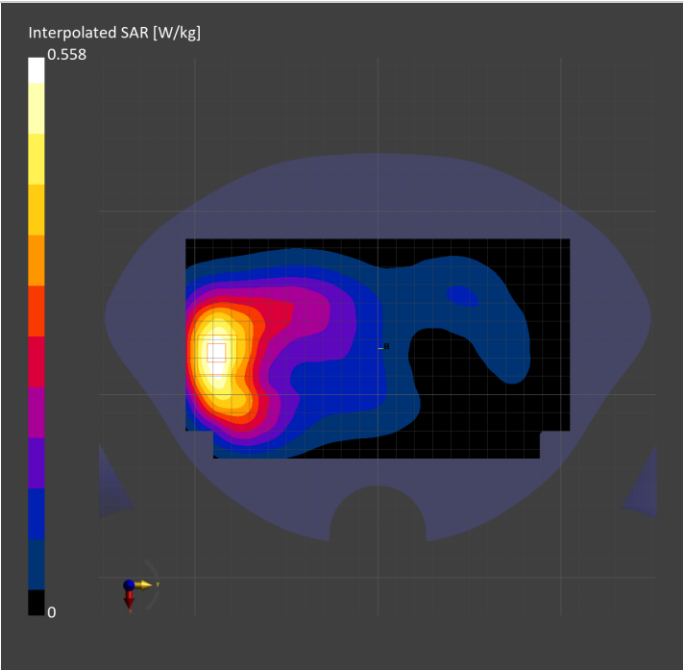
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-04-22	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-22	2025-04-22
psSAR1g [W/kg]	0.459	0.467
psSAR10g [W/kg]	0.274	0.285
Power Drift [dB]	-0.00	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.3
Dist 3dB Peak [mm]		16.8



P20 WCDMA IV_RMC12.2K_Rear Face_1.5cm_Ch1312

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 4	WCDMA, -	1712.400, 1312	8.6	1.32	41.5

Hardware Setup

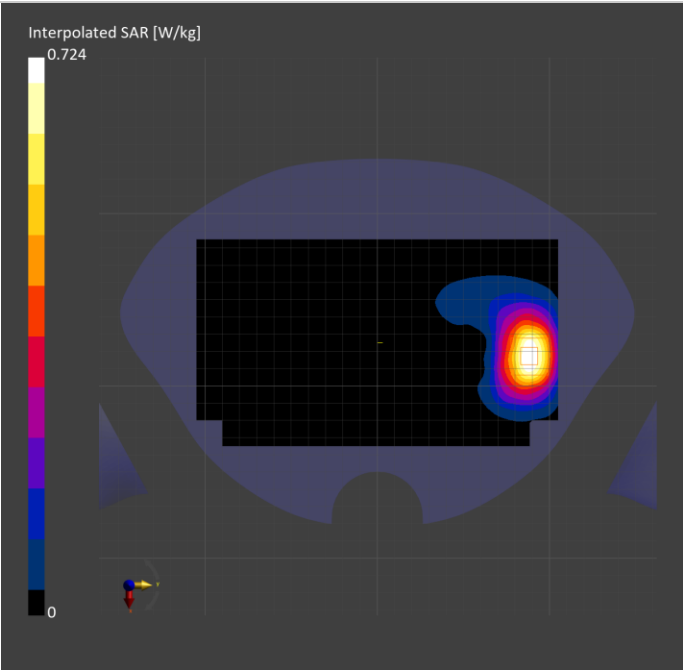
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-04-23	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-23	2025-04-23
psSAR1g [W/kg]	0.602	0.649
psSAR10g [W/kg]	0.344	0.363
Power Drift [dB]	-0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.3
Dist 3dB Peak [mm]		12.0



P21 WCDMA V_RMC12.2K_Rear Face_1.5cm_Ch4132

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 5	WCDMA, -	826,400, 4132	9.75	0.916	43.4

Hardware Setup

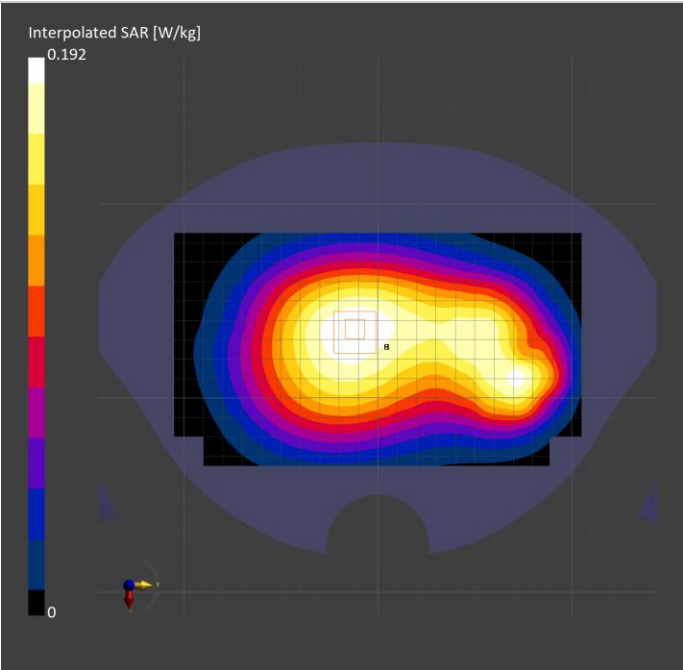
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-04-21	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-21	2025-04-21
psSAR1g [W/kg]	0.169	0.179
psSAR10g [W/kg]	0.119	0.135
Power Drift [dB]	0.01	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		90.3
Dist 3dB Peak [mm]		> 15.0



P22 LTE B2_QPSK20M_Rear Face_1.5cm_Ch18900_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 2	LTE-FDD, -	1880.000, 18900	8.25	1.38	40.8

Hardware Setup

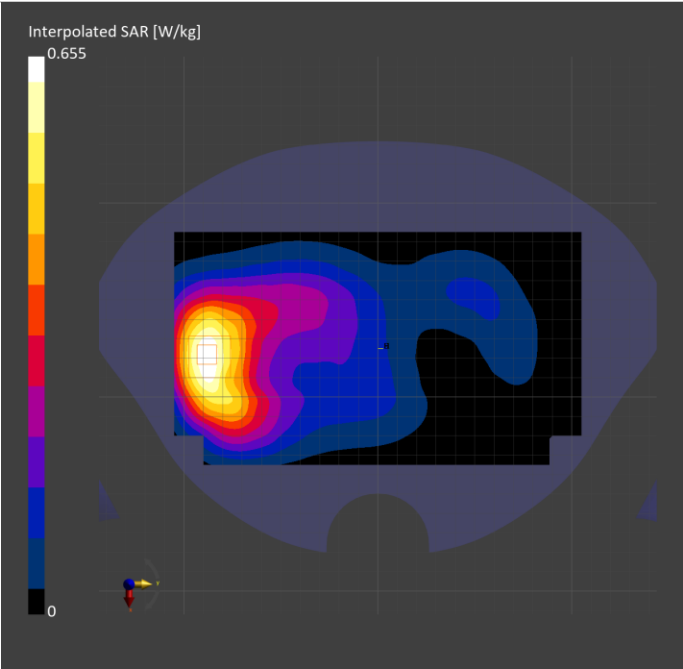
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-04-22	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-22	2025-04-22
psSAR1g [W/kg]	0.540	0.551
psSAR10g [W/kg]	0.322	0.336
Power Drift [dB]	0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.7
Dist 3dB Peak [mm]		16.1



P23 LTE B7_QPSK20M_Rear Face_1.5cm_Ch20850_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 7	LTE-FDD, -	2510.000, 20850	7.57	1.89	37.8

Hardware Setup

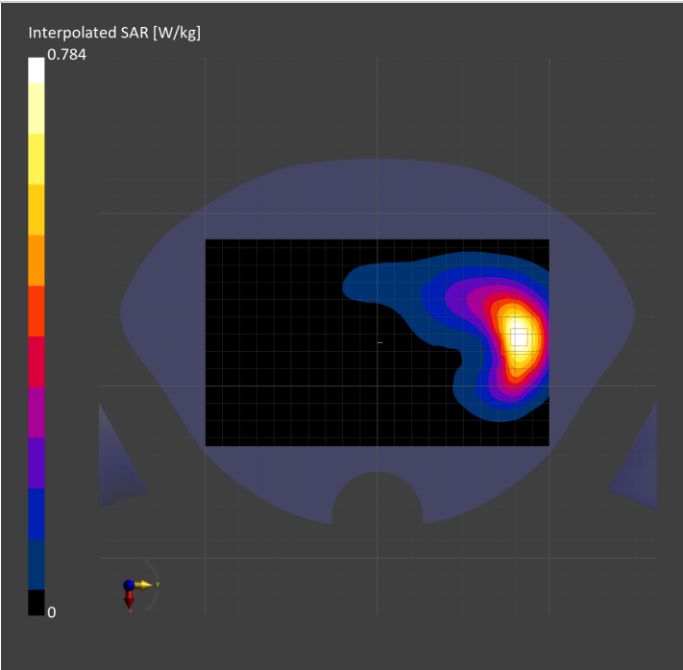
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-04-24	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-24	2025-04-24
psSAR1g [W/kg]	0.626	0.626
psSAR10g [W/kg]	0.323	0.322
Power Drift [dB]	-0.07	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		11.5



P24 LTE B13_QPSK10M_Rear Face_1.5cm_Ch23230_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 13	LTE-FDD, -	782.000, 23230	10.21	0.898	43.6

Hardware Setup

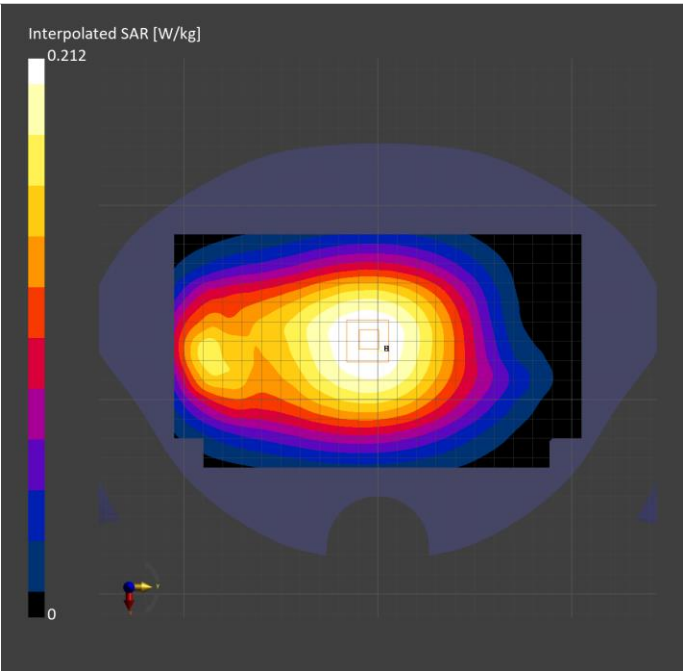
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL750-2025-04-25	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-25	2025-04-25
psSAR1g [W/kg]	0.188	0.201
psSAR10g [W/kg]	0.134	0.153
Power Drift [dB]	-0.00	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		89.8
Dist 3dB Peak [mm]		> 15.0



P25 LTE B26_QPSK15M_Rear Face_1.5cm_Ch26965_1RB_OS37

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 26	LTE-FDD, -	841.500, 26965	9.75	0.923	43.4

Hardware Setup

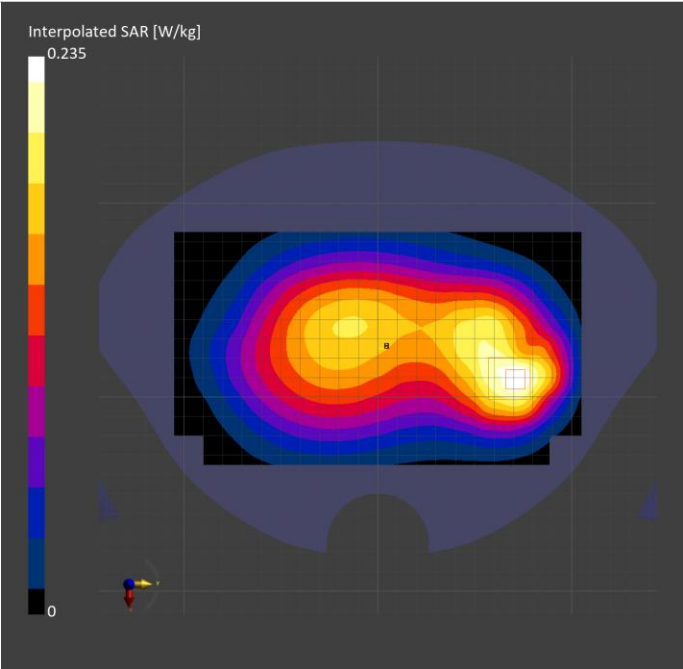
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-04-21	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-21	2025-04-21
psSAR1g [W/kg]	0.202	0.201
psSAR10g [W/kg]	0.135	0.124
Power Drift [dB]	0.03	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.6
Dist 3dB Peak [mm]		14.0



P26 LTE B41_QPSK20M_Rear Face_1.5cm_Ch40620_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 41	LTE-TDD, -	2593.000, 40620	7.57	1.94	37.7

Hardware Setup

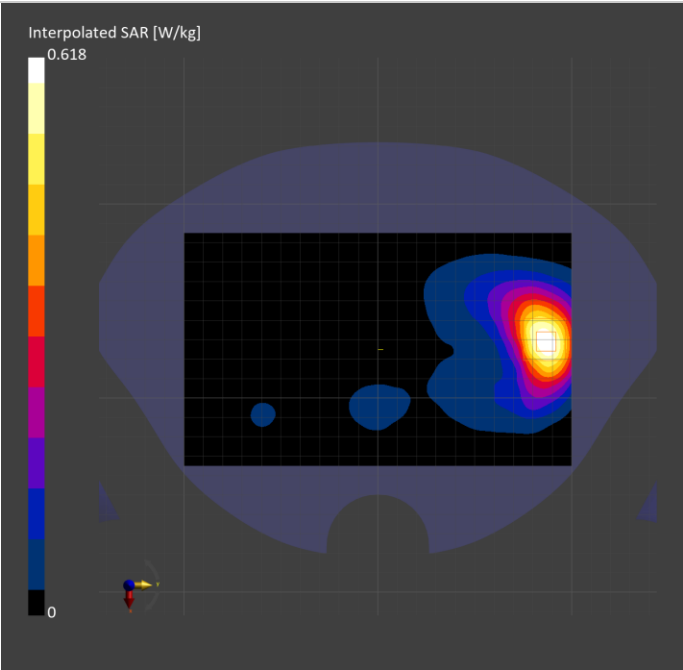
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-04-24	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-24	2025-04-24
psSAR1g [W/kg]	0.492	0.498
psSAR10g [W/kg]	0.257	0.259
Power Drift [dB]	-0.02	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.5
Dist 3dB Peak [mm]		12.7



P27 LTE B66_QPSK20M_Rear Face_1.5cm_Ch132072_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 66	LTE-FDD, -	1720.000, 132072	8.6	1.32	41.5

Hardware Setup

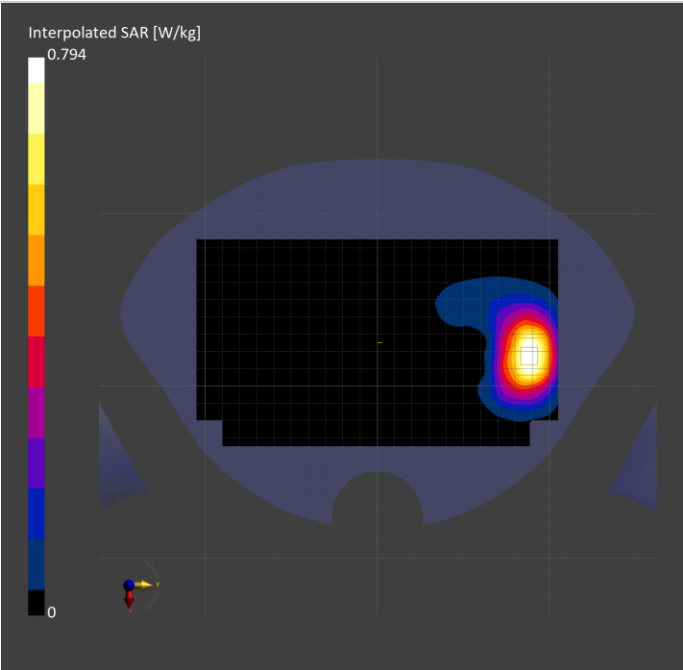
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-04-23	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-23	2025-04-23
psSAR1g [W/kg]	0.662	0.730
psSAR10g [W/kg]	0.378	0.407
Power Drift [dB]	0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.9
Dist 3dB Peak [mm]		11.9



P28 WLAN 2.4G_802.11b_Rear Face_1.5cm_Ch1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 2.4GHz	WLAN, -	2412.000, 1	7.7	1.81	38.0

Hardware Setup

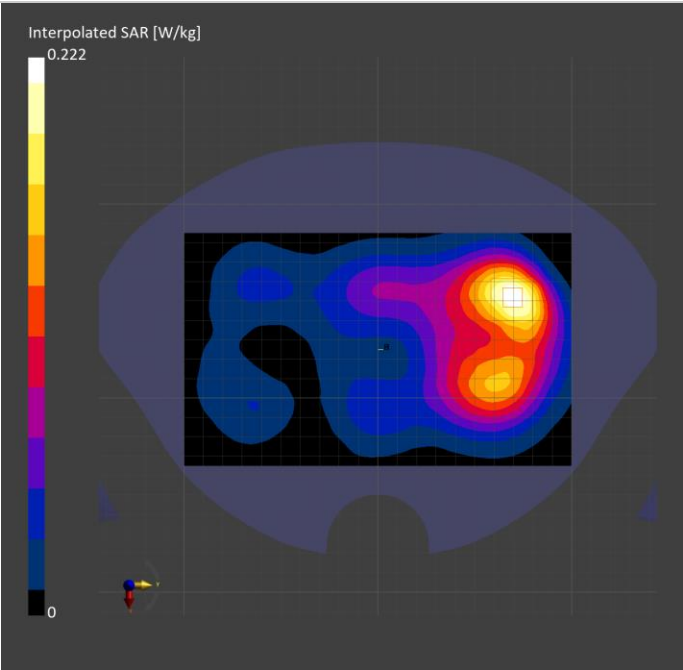
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-04-30	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-30	2025-04-30
psSAR1g [W/kg]	0.178	0.179
psSAR10g [W/kg]	0.097	0.097
Power Drift [dB]	-0.03	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.4
Dist 3dB Peak [mm]		14.2



P29 WLAN 5G_802.11a_Rear Face_1.5cm_Ch60

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5300.000, 60	4.99	4.65	36.2

Hardware Setup

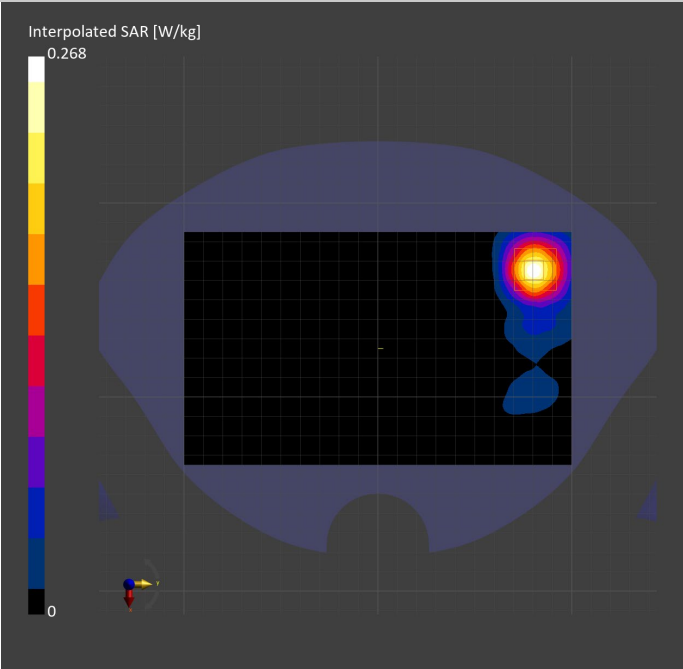
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-04-29	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-29	2025-04-29
psSAR1g [W/kg]	0.206	0.227
psSAR10g [W/kg]	0.077	0.084
Power Drift [dB]	-0.01	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.0
Dist 3dB Peak [mm]		10.9



P30 WLAN5G_802.11a_Rear Face_1.5cm_Ch100

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5500.000, 100	4.65	4.88	35.8

Hardware Setup

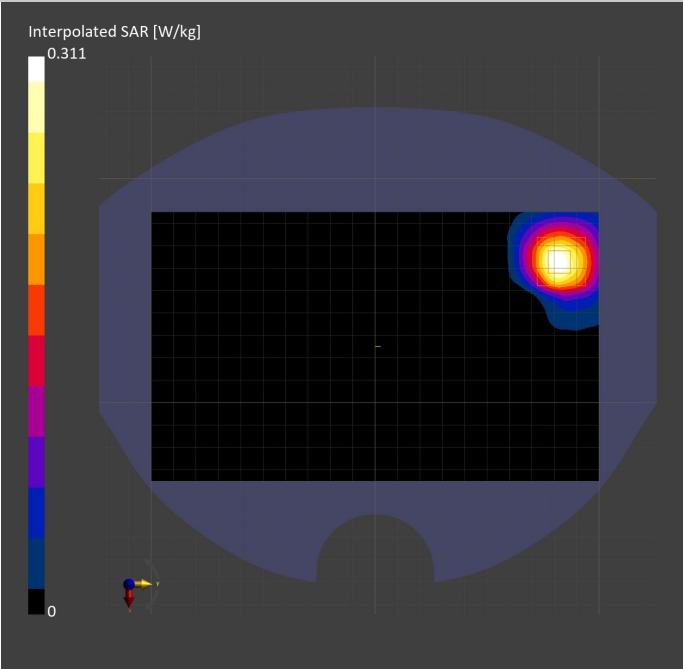
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-04-29	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-29	2025-04-29
psSAR1g [W/kg]	0.228	0.232
psSAR10g [W/kg]	0.088	0.084
Power Drift [dB]	-0.62	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		67.0
Dist 3dB Peak [mm]		9.0



P31 WLAN5G_802.11a_Rear Face_1.5cm_Ch149

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5745.000, 149	4.76	5.17	35.4

Hardware Setup

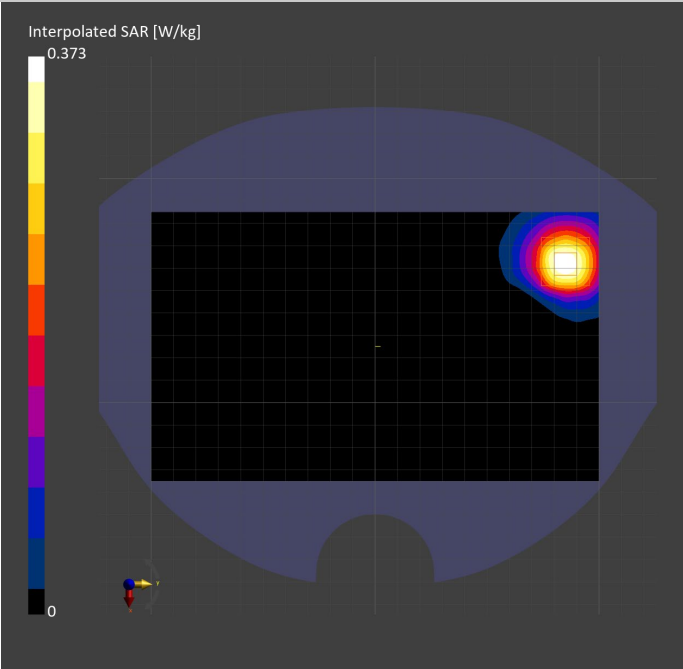
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-04-30	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-30	2025-04-30
psSAR1g [W/kg]	0.283	0.289
psSAR10g [W/kg]	0.110	0.107
Power Drift [dB]	-0.09	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.5
Dist 3dB Peak [mm]		10.2



P32 BT_GFSK_Rear Face_1.5cm_Ch39

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	ISM 2.4 GHz Band	Bluetooth, -	2441.000, 39	7.7	1.83	37.9

Hardware Setup

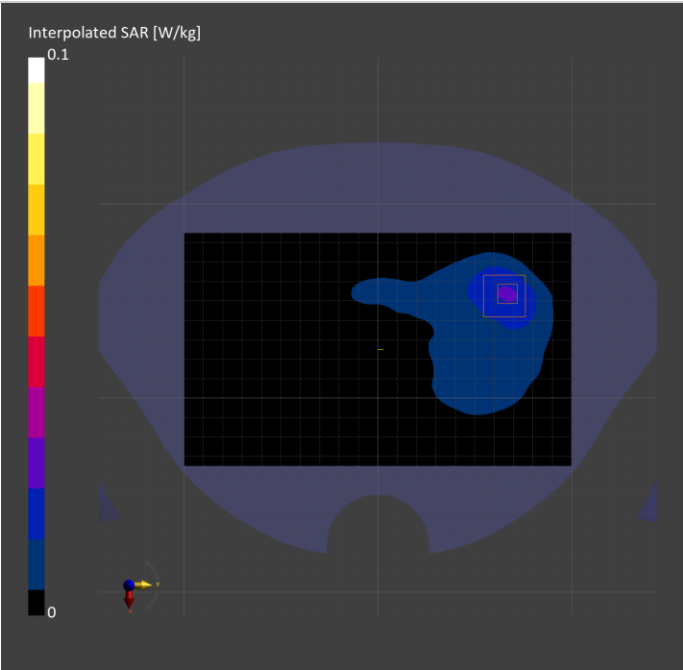
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-04-30	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-30	2025-04-30
psSAR1g [W/kg]	0.021	0.021
psSAR10g [W/kg]	0.011	0.011
Power Drift [dB]	-0.18	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.9
Dist 3dB Peak [mm]		14.3



P33 GSM850_GPRS 1Tx Slot_Rear Face_1cm_Ch251

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	GSM 850	GSM, -	848.800, 251	9.75	0.925	43.4

Hardware Setup

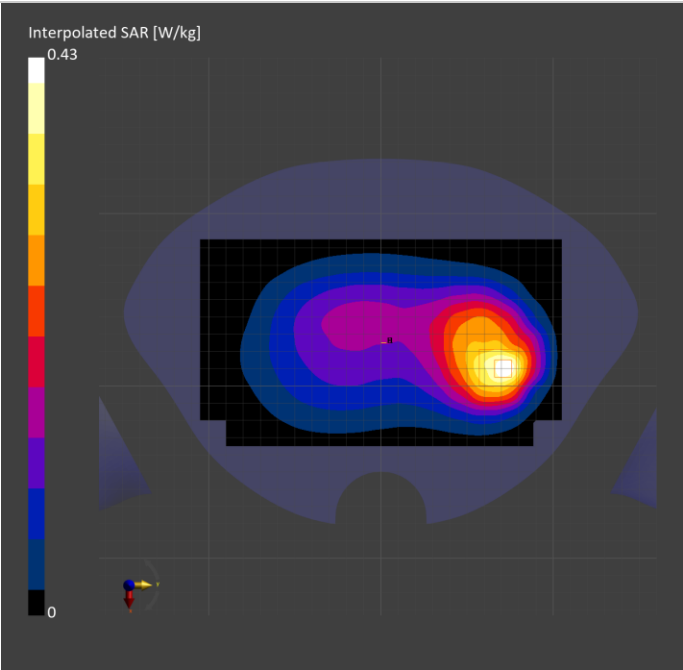
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-04-21	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-21	2025-04-21
psSAR1g [W/kg]	0.361	0.351
psSAR10g [W/kg]	0.231	0.203
Power Drift [dB]	0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.7
Dist 3dB Peak [mm]		10.2



P34 GSM1900_GPRS 1Tx Slot_Top Side_1cm_Ch661

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE Top, 10.00	PCS 1900	GSM, -	1880.000, 661	8.25	1.38	40.8

Hardware Setup

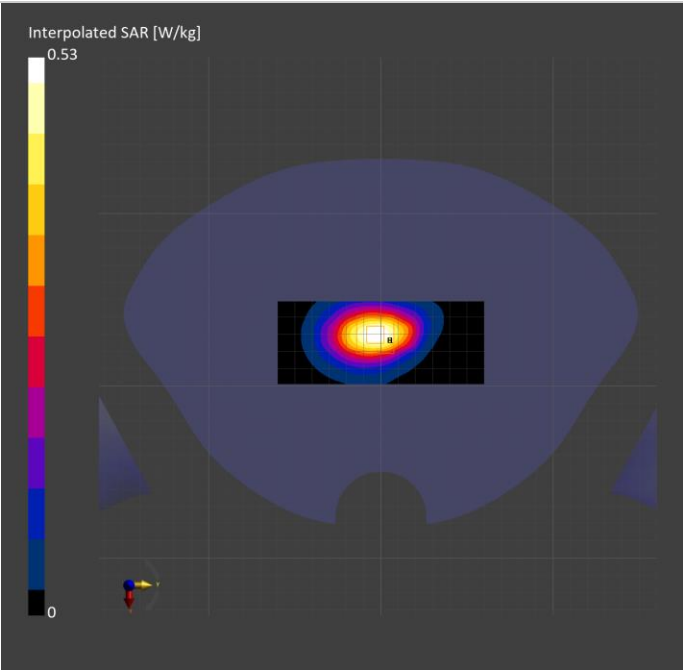
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-04-22	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-22	2025-04-22
psSAR1g [W/kg]	0.432	0.442
psSAR10g [W/kg]	0.236	0.247
Power Drift [dB]	-0.00	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.6
Dist 3dB Peak [mm]		12.0



P35 WCDMA II_RMC12.2K_Bottom Side_1cm_Ch9262

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 2	WCDMA, -	1852.400, 9262	8.25	1.36	40.9

Hardware Setup

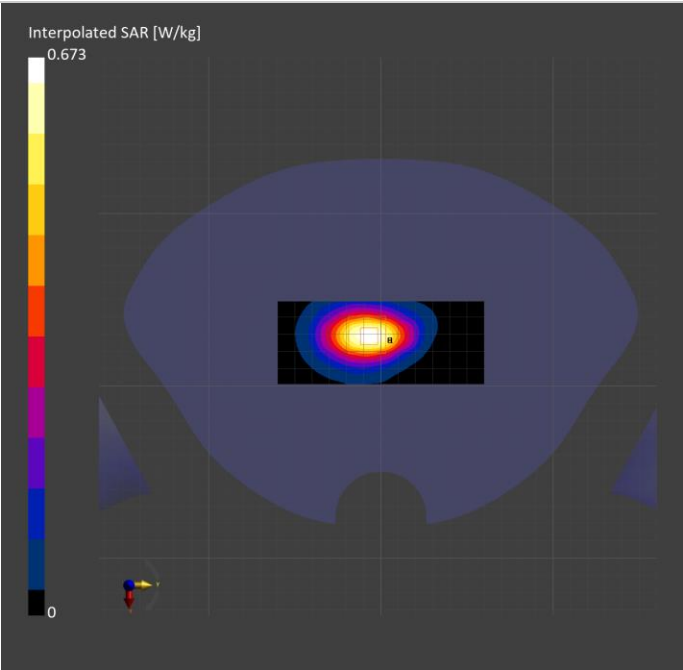
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-04-22	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-22	2025-04-22
psSAR1g [W/kg]	0.546	0.556
psSAR10g [W/kg]	0.297	0.308
Power Drift [dB]	0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.0
Dist 3dB Peak [mm]		11.9



P36 WCDMA IV_RMC12.2K_Bottom Side_1cm_Ch1513

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 4	WCDMA, -	1752.600, 1513	8.6	1.34	41.4

Hardware Setup

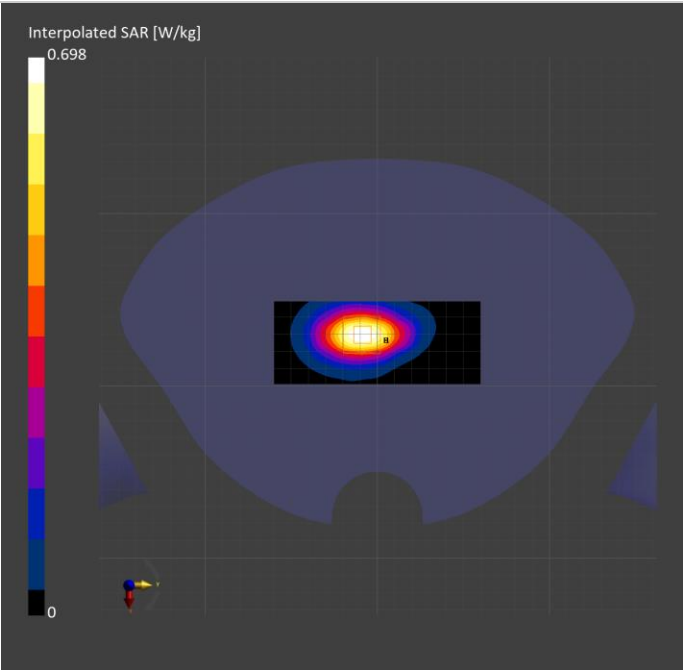
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-04-23	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-23	2025-04-23
psSAR1g [W/kg]	0.568	0.582
psSAR10g [W/kg]	0.311	0.323
Power Drift [dB]	-0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.7
Dist 3dB Peak [mm]		11.1



P37 WCDMA V_RMC12.2K_Rear Face_1cm_Ch4233

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 5	WCDMA, -	846.600, 4233	9.75	0.916	43.4

Hardware Setup

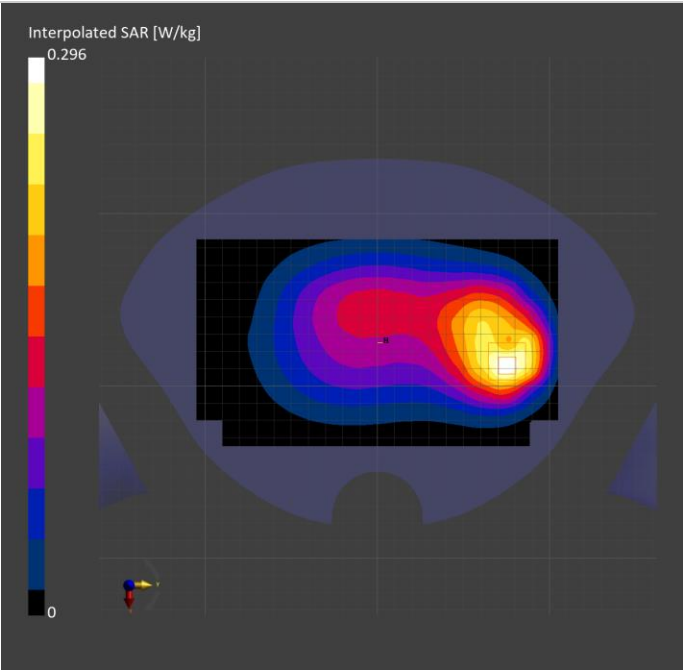
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-04-21	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-21	2025-04-21
psSAR1g [W/kg]	0.249	0.251
psSAR10g [W/kg]	0.162	0.147
Power Drift [dB]	0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.8
Dist 3dB Peak [mm]		10.8



P38 LTE B2_QPSK20M_Bottom Side_1cm_Ch18700_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 2	LTE-FDD, -	1860.000, 18700	8.25	1.37	40.8

Hardware Setup

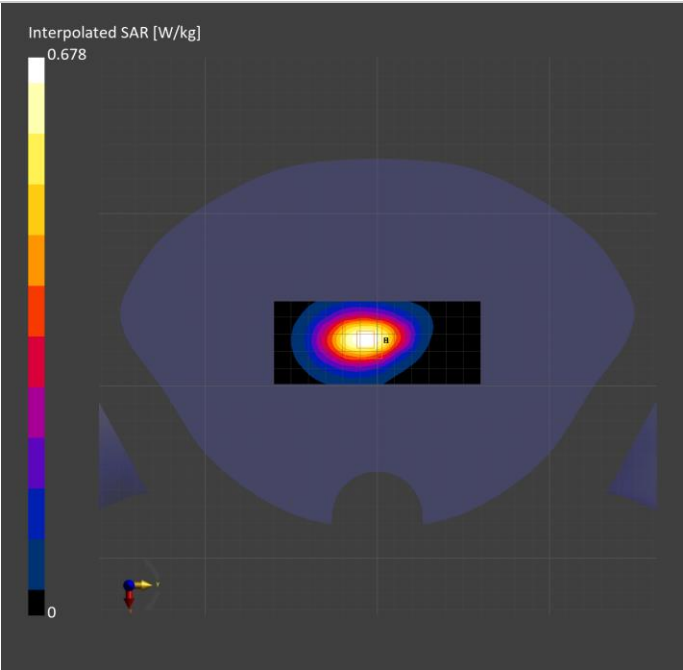
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-04-22	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-22	2025-04-22
psSAR1g [W/kg]	0.548	0.559
psSAR10g [W/kg]	0.298	0.310
Power Drift [dB]	0.01	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.3
Dist 3dB Peak [mm]		11.9



P39 LTE B7_QPSK20M_Bottom Side_1cm_Ch21350_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 7	LTE-FDD, -	2560.000, 21350	7.57	1.90	37.8

Hardware Setup

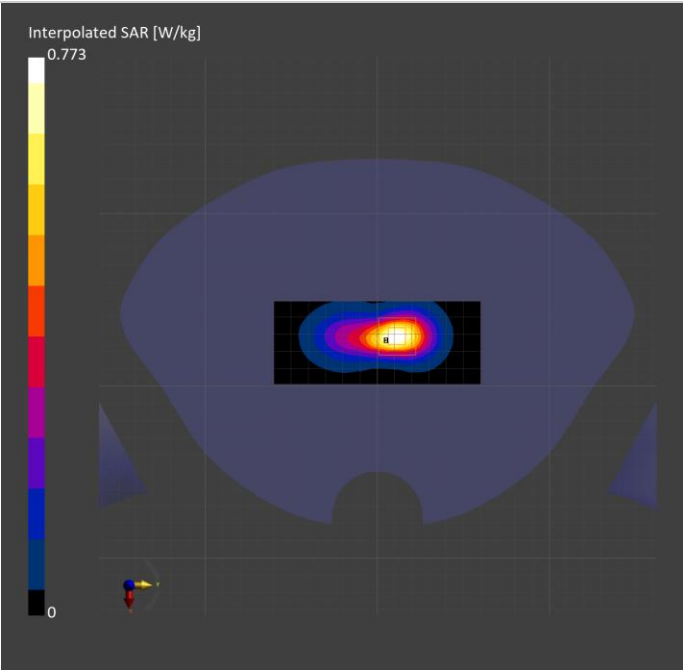
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-04-24	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-24	2025-04-24
psSAR1g [W/kg]	0.591	0.604
psSAR10g [W/kg]	0.273	0.277
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.0
Dist 3dB Peak [mm]		9.0



P40 LTE B13_QPSK10M_Rear Face_1cm_Ch23230_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 13	LTE-FDD, -	782.000, 23230	10.21	0.897	43.6

Hardware Setup

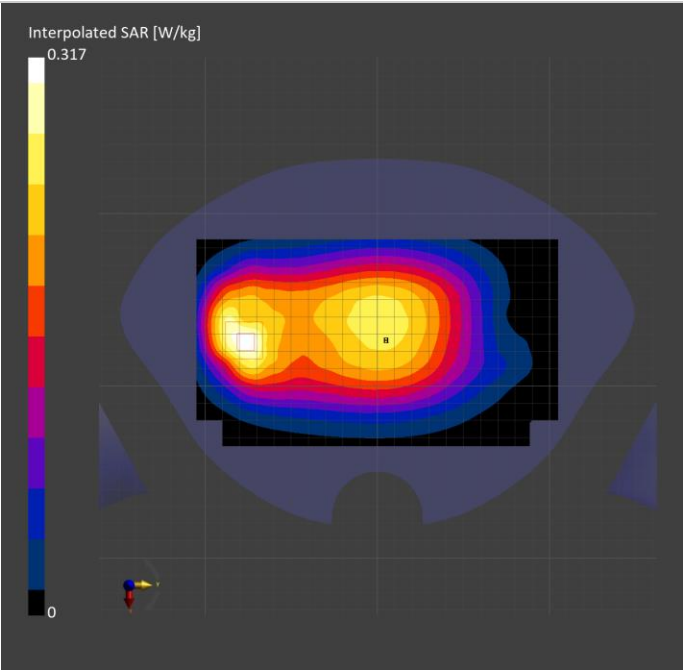
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL750-2025-04-25	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-25	2025-04-25
psSAR1g [W/kg]	0.271	0.278
psSAR10g [W/kg]	0.179	0.163
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.1
Dist 3dB Peak [mm]		12.8



P41 LTE B26_QPSK15M_Rear Face_1cm_Ch26956_1RB_OS37

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 26	LTE-FDD, -	841.500, 26965	9.75	0.92	43.4

Hardware Setup

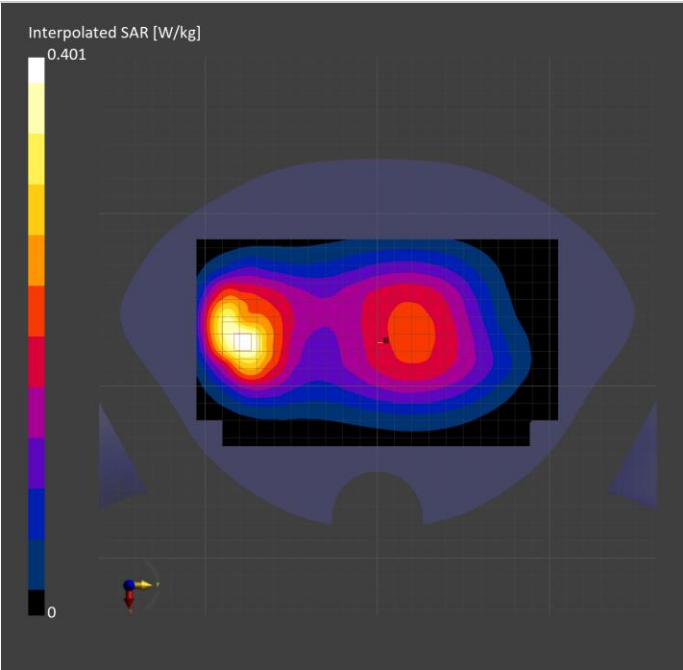
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-04-21	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-21	2025-04-21
psSAR1g [W/kg]	0.342	0.356
psSAR10g [W/kg]	0.221	0.205
Power Drift [dB]	-0.00	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.8
Dist 3dB Peak [mm]		12.4



P42 LTE B41_QPSK20M_Bottom Side_1cm_Ch40620_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 41	LTE-TDD, -	2593.000, 40620	7.57	1.94	37.7

Hardware Setup

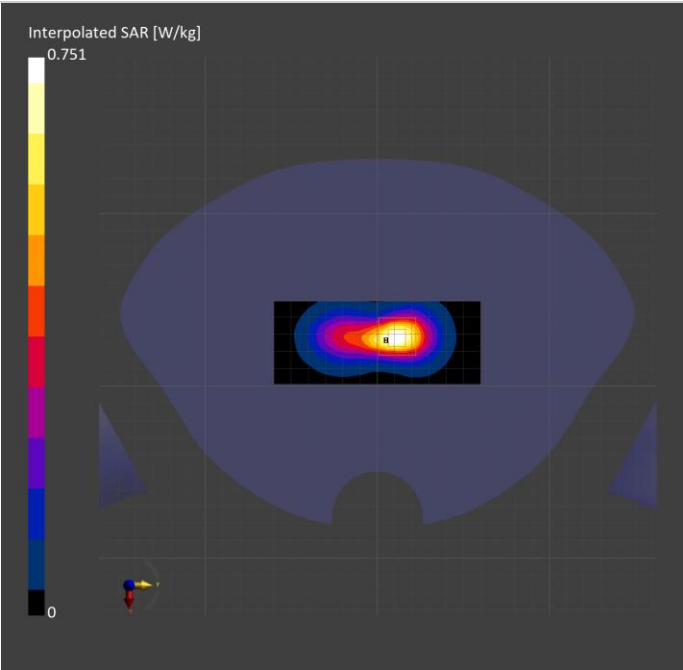
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-04-24	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-24	2025-04-24
psSAR1g [W/kg]	0.573	0.588
psSAR10g [W/kg]	0.267	0.272
Power Drift [dB]	-0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.2
Dist 3dB Peak [mm]		9.0



P43 LTE B66_QPSK20M_Bottom Side_1cm_Ch132572_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 66	LTE-FDD, -	1770.000, 132572	8.6	1.34	41.5

Hardware Setup

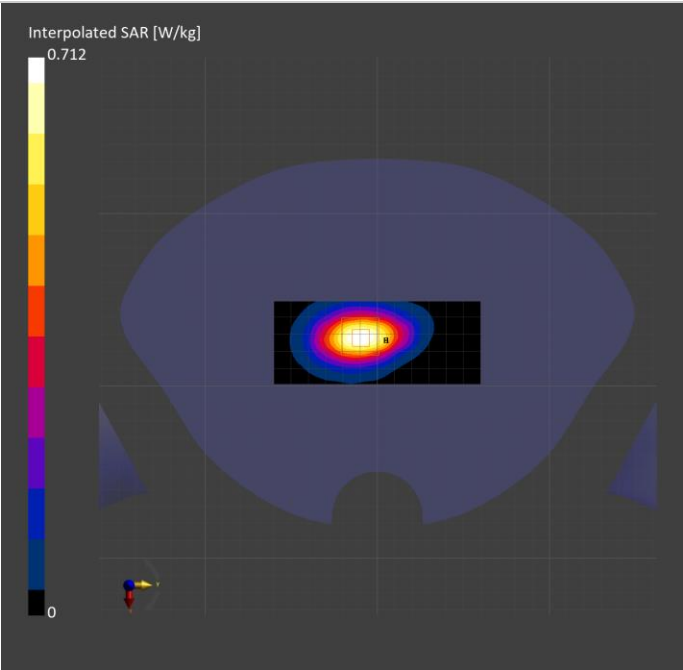
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-04-23	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-23	2025-04-23
psSAR1g [W/kg]	0.579	0.592
psSAR10g [W/kg]	0.317	0.330
Power Drift [dB]	0.01	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.1
Dist 3dB Peak [mm]		11.1



P44 WLAN 2.4G_802.11b_Rear Face_1cm_Ch1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	WLAN 2.4GHz	WLAN, -	2412.000, 1	7.7	1.8	38.0

Hardware Setup

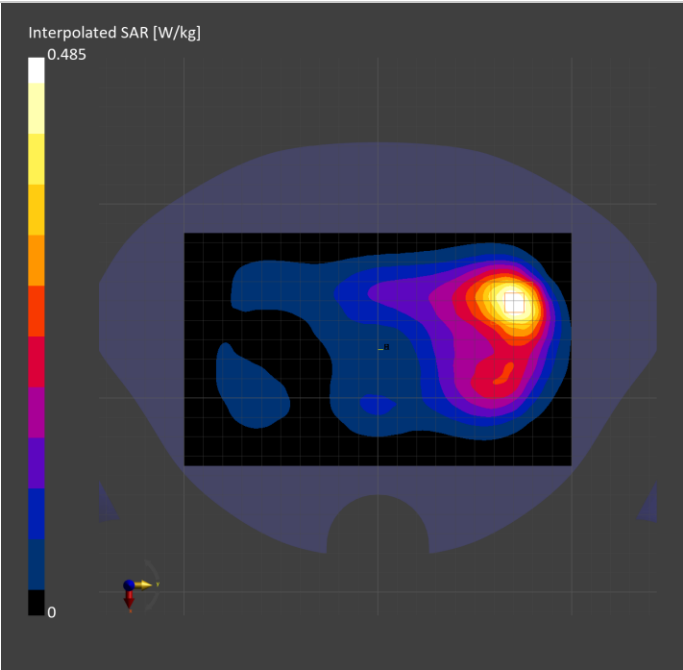
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-04-30	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-30	2025-04-30
psSAR1g [W/kg]	0.392	0.384
psSAR10g [W/kg]	0.208	0.199
Power Drift [dB]	0.00	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.9
Dist 3dB Peak [mm]		12.6



P45 WLAN5G_802.11a_Top Side_1cm_Ch48

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 10.00	WLAN 5GHz	WLAN, -	5240.000, 48	5.18	4.58	36.3

Hardware Setup

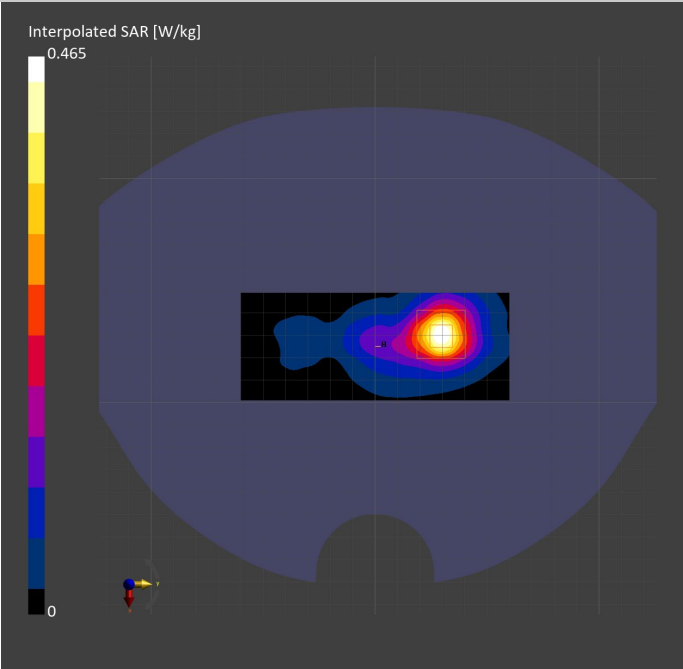
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-04-29	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-29	2025-04-29
psSAR1g [W/kg]	0.326	0.361
psSAR10g [W/kg]	0.118	0.129
Power Drift [dB]	0.14	0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.6
Dist 3dB Peak [mm]		9.8



P46 WLAN5G_802.11a_Rear Face_1cm_Ch149

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	WLAN 5GHz	WLAN, -	5745.000, 149	4.76	5.17	35.4

Hardware Setup

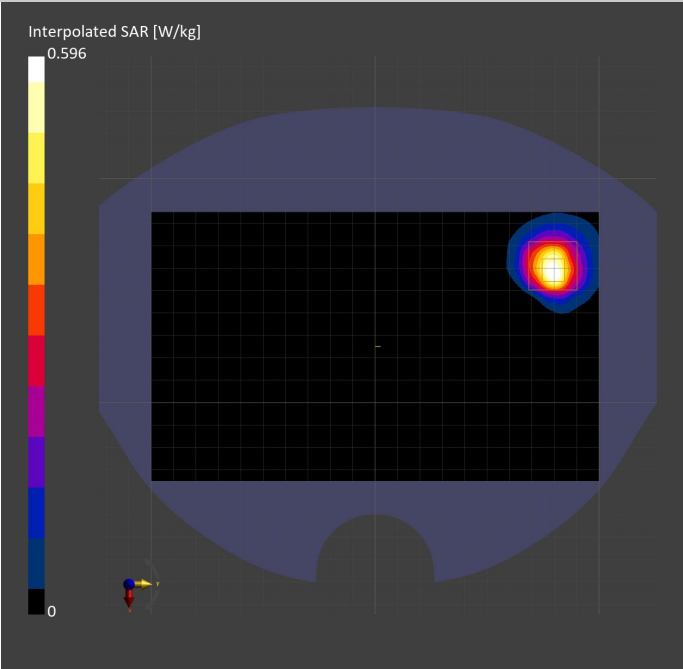
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-04-30	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-30	2025-04-30
psSAR1g [W/kg]	0.427	0.426
psSAR10g [W/kg]	0.143	0.143
Power Drift [dB]	-0.01	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		60.7
Dist 3dB Peak [mm]		8.6



P47 BT_GFSK_Rear Face_1cm_Ch39

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	ISM 2.4 GHz Band	Bluetooth, -	2441.000, 39	7.7	1.83	37.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-04-30	EX3DV4 - SN7801, 2025-03-11	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-04-30	2025-04-30
psSAR1g [W/kg]	0.044	0.037
psSAR10g [W/kg]	0.023	0.019
Power Drift [dB]	-0.00	0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.1
Dist 3dB Peak [mm]		11.2

